

PLUS Search Results for S/N 10689553, Searched March 24, 2005

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5630051
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5617531 56
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5015875 55
6070258 55
6028988 55
5680332 54
6594802 54
6195025 52
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5239270 49
5574733 48
4630928 48
4831560 48
4876702 48
4931800 48
5276897 48
5333197 48
5408956 48
5716856 48
5831995 48
5930138 48
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10689553_CLS.txt
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10689553 on March 24, 2005

Original Classifications

7 714/738
4 714/724
2 702/183
2 716/4

Cross-Reference Classifications

4 714/718
3 714/734
3 714/736
3 716/4
2 257/E21.525
2 702/185
2 714/704
2 714/723
2 714/733
2 714/738
2 716/2
2 716/5
2 716/6

Combined Classifications

9 714/738
5 714/724
5 716/4
4 714/718
3 714/734
3 714/736
2 257/E21.525
2 365/201
2 438/14
2 702/183
2 702/185
2 714/33
2 714/704
2 714/723
2 714/727
2 714/733
2 716/2
2 716/5
2 716/6

Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10689553 on March 24, 2005

- 9 714/738 (7 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/738 ..Including test pattern generator
- 5 714/724 (4 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
- 5 716/4 (2 OR, 3 XR)
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK
716/1 CIRCUIT DESIGN
716/4 .Testing or evaluating
- 4 714/718 (0 OR, 4 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/718 .Memory testing
- 3 714/734 (0 OR, 3 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/734 ..Structural (in-circuit test)
- 3 714/736 (0 OR, 3 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/736 ..Device response compared to expected
fault-free response
- 2 257/E21.525 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/E21.515Involving use of mechanical auxiliary part
without use of alloying or soldering process, e.g.,
pressure contacts (EPO)
257/E21.521 .Testing or measuring during manufacture or
treatment or reliability measurement, i.e., testing of
parts followed by no processing which modifies parts as
such (EPO)
257/E21.525 ..Procedures, i.e., sequence of activities
consisting of plurality of measurement and correction,
marking or sorting steps (EPO)
- 2 365/201 (1 OR, 1 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/201 .Testing
- 2 438/14 (1 OR, 1 XR)

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Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
438/14 WITH MEASURING OR TESTING

2 702/183 (2 OR, 0 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/127 MEASUREMENT SYSTEM
702/182 .Performance or efficiency evaluation
702/183 ..Diagnostic analysis

2 702/185 (0 OR, 2 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/127 MEASUREMENT SYSTEM
702/182 .Performance or efficiency evaluation
702/183 ..Diagnostic analysis
702/185 ...Cause or fault identification

2 714/33 (1 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
714/1 .Reliability and availability
714/25 ..Fault locating (i.e., diagnosis or testing)
714/32 ...Particular stimulus creation
714/33 ....Derived from analysis (e.g., of a
specification or by stimulation)

2 714/704 (0 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/704 .Error count or rate

2 714/723 (0 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/718 .Memory testing
714/723 ..Error mapping or logging

2 714/727 (1 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))
714/727 ...Boundary scan

2 714/733 (0 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/733 ..Built-in testing circuit (BILBO)

2 716/2 (0 OR, 2 XR)
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK

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716/1      CIRCUIT DESIGN
716/2      .Optimization (e.g., redundancy, compaction)

2  716/5      (0 OR, 2 XR)
      Class  716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
                CIRCUIT OR SEMICONDUCTOR MASK
716/1      CIRCUIT DESIGN
716/4      .Testing or evaluating
716/5      ..Design verification (e.g., wiring line
                capacitance, fan-out checking, minimum path width)

2  716/6      (0 OR, 2 XR)
      Class  716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
                CIRCUIT OR SEMICONDUCTOR MASK
716/1      CIRCUIT DESIGN
716/4      .Testing or evaluating
716/5      ..Design verification (e.g., wiring line
                capacitance, fan-out checking, minimum path width)
716/6      ...Timing analysis (e.g., delay time, path
                delay, latch timing)

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4876702
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5333197
5408956
5716856
5831995
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5943640
6067639
6088664
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 abstmct 1
 academically 1
 according 2
 action 2
 addition 2
 algorithm 3
 algorithms 2
 all 3
 almost 1
 also 3
 am 2
 an 4
 and 43
 another 3
 appamtus 1
 apparatus 5
 application 1
 applied 1
 applies 1
 apply 2
 applying 2
 are 6
 art 1
 as 6
 assignment 1
 attached 1
 automation 1
 based 4
 be 9
 behavior 1
 belief 1
 best 1
 brief 1
 but 1
 by 19
 cal 1
 called 2
 can 8
 case 2
 cause 1
 certification 1
 certify 1
 check 13
 checked 3
 chome 1
 combinatorial 1
 common 2
 communication 14
 complete 3
 composition 2
 concatenate 2
 concatenating 2
 conformance 1
 conjunctive 4
 consider 1
 considering 5
 constraints 2
 construct 1
 construction 1
 constructs 1
 contained 1
 conventional 3

conversant 1
convert 1
converting 6
converts 3
correct 1
correctly 5
correctness 2
corresponding 2
data 1
date 1
declare 1
depends 1
derived 1
described 5
describing 2
description 3
design 1
detmled 1
dhcp 1
diagram 22
diaram 1
disclosure 1
distinguish 1
do 1
document 1
does 1
drawings 1
ds 2
each 6
eakawa 1
either 1
electronic 1
embodiment 9
english 2
execute 3
executed 1
executing 4
exist 1
existence 2
exists 5
field 1
fig 24
finite 3
first 3
flowchart 1
following 1
for 28
form 4
formqla 1
formula 5
from 3
fsm 34
fsms 1
furthermore 1
genemte 1
general 2
generate 19
generated 4
generates 7
generating 10
generation 16
get 1
given 11

hand 1
has 1
have 6
here 2
however 2
identify 1
if 3
ilowchart 1
implementation 4
implemented 6
improved 1
in 25
ing 1
initial 2
input 11
inputting 3
into 1
invention 19
inwntion 1
is 44
it 1
its 2
iut 8
japanease 1
jts 1
knowledge 1
known 2
ku 1
languages 1
lead 1
length 8
lenlh 1
like 1
lo 1
longer 1
loops 1
lune 1
machine 3
machines 2
maximum 2
may 3
method 8
methods 2
minimum 5
modeled 1
modi 1
modified 6
modifying 2
more 1
moves 1
multiple 4
my 1
nao 2
needed 1
nippori 1
nishi 1
no 1
nor 1
normal 4
not 3
np 3
obtain 1
obtained 3

oda 2
of 79
on 7
one 1
only 1
optimization 1
or 7
order 1
other 2
output 7
overlap 1
overlapping 7
page 8
particularly 1
parts 2
patent 1
performance 1
pertains 1
practical 2
preceding 7
prefered 1
present 17
problem 39
problems 2
process 1
proposed 1
proposes 3
protocol 10
protocols 12
quickly 1
recently 1
related 1
relates 2
represented 1
representing 8
represents 1
reset 2
result 6
return 1
sat 19
satisfiability 1
satisfiable 2
second 4
section 4
selection 1
self 1
sequences 1
sequence 56
sequences 44
serial 1
shorter 2
should 1
shows 23
since 2
single 1
so 2
solver 2
solves 1
solving 5
sometimes 1
specification 11
specilcation 1
state 36

states 8
 step 12
 subsequence 3
 subsequences 4
 such 4
 summary 1
 technical 1
 technique 1
 test 66
 tested 1
 testing 1
 that 5
 the 217
 then 2
 there 5
 these 2
 time 2
 title 1
 to 56
 tokyoylapuyhereby 1
 transition 10
 transitions 7
 translation 1
 translator 2
 true 1
 truth 1
 two 1
 ui 3
 uio 19
 uios 1
 under 2
 unique 1
 use 2
 using 2
 value 1
 variables 1
 we 14
 when 4
 whether 11
 whi 1
 which 36
 with 1
 without 1
 would 1
 xq 1
 xsxq 1